



1/25/2008

RELIABILITY MONITOR REPORT
FOR

SAT 0.4 μ m Silicon Gate CMOS

MAXIM Integrated Products

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This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX8611ETM+	MAX9853ETM+
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 33137** **FITS: 3.4**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

Process Information:

Process Description: SAT 0.4µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0629	MAX9853ETM+	135C, 5.25V	1000 HRS	77	0	
		MAX8611ETM+	135C, 5.25V	1000 HRS	48	0	
HIGH TEMP OP LIFE	0630	MAX8611ETM+	135C, 5.25V	1000 HRS	46	0	
Total:						0	

FAILURE RATE: **MTTF (YRS): 33137** **FITS: 3.4**